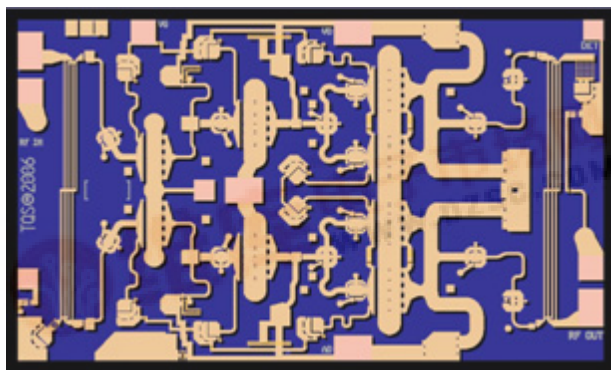


K Band High Linearity Power Amplifier

TGA4530

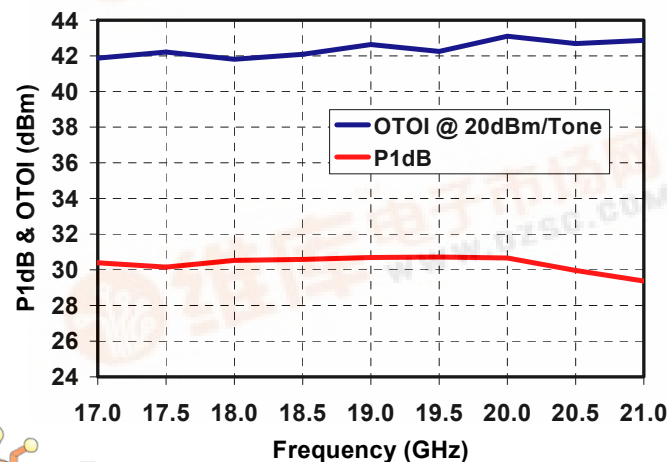
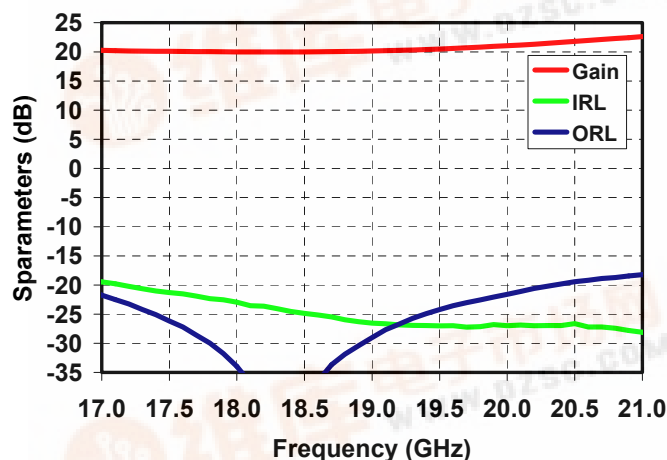


Key Features

- Frequency Range: 17 - 21 GHz
- 20 dB Gain
- 30 dBm nominal P1dB
- 42dBm nominal OTOI
- 20 dB Return Loss
- Bias 5 - 7 V @ 825 mA
- 0.25 um 3MI pHEMT technology
- Chip Dimensions 2.43 x 1.45 x .1mm

Measured Fixtured Data

Bias Conditions: $V_d = 7V$, $I_d = 825mA$



Primary Applications

- Point-to-Point Radio
- K Band Sat-Com

Product Description

The TriQuint TGA4530 is a High Power Amplifier MMIC for 17 – 21GHz applications. The part is designed using TriQuint's 0.25um 3MI pHEMT production process.

The TGA4530 nominally provides 30dBm output power @ 1dB gain compression and 42dBm OTOI at a bias of 7V and 825mA. The typical gain is 20dB.

The part is ideally suited for low cost emerging markets such as Point-to-Point Radio, and K-band Satellite Communications.

The TGA4530 is 100% DC and RF tested on-wafer to ensure performance compliance.

The TGA4530 has a protective surface passivation layer providing environmental robustness.

Lead-Free & RoHS compliant

TABLE I
MAXIMUM RATINGS 1/

SYMBOL	PARAMETER	VALUE	NOTES
V _d	Positive Supply Voltage	8 V	<u>2/</u>
V _g	Negative Supply Voltage Range	-5V TO 0V	
I _d	Positive Supply Current	1.75 A	<u>2/</u>
I _G	Gate Supply Current	35 mA	
P _{IN}	Input Continuous Wave Power	26 dBm	<u>2/</u>
P _D	Power Dissipation	5.8 W	<u>2/</u> , <u>3/</u>
T _{CH}	Operating Channel Temperature	150 °C	<u>3/</u> , <u>4/</u>
T _M	Mounting Temperature (30 Seconds)	320 °C	
T _{STG}	Storage Temperature	-65 to 150 °C	

- 1/ These ratings represent the maximum operable values for this device.
- 2/ Combinations of supply voltage, supply current, input power, and output power shall not exceed P_D.
- 3/ When operated at this power dissipation with a base plate temperature of 65⁰C, the median life is 1.0E+6 hrs.
- 4/ Junction operating temperature will directly affect the device median time to failure (MTTF). For maximum life, it is recommended that junction temperatures be maintained at the lowest possible levels.

TABLE II
ELECTRICAL CHARACTERISTICS
(Ta = 25 °C Nominal)

PARAMETER	TYPICAL	UNITS
Frequency Range	17 - 21	GHz
Drain Voltage, Vd	7	V
Drain Current, Id	825	mA
Gate Voltage, Vg	-0.45	V
Small Signal Gain, S21	20	dB
Input Return Loss, S11	20	dB
Output Return Loss, S22	20	dB
Saturated Output Power @ Pin = 16dBm, Psat	32	dBm
Output Power @ 1dB Gain Compression, P1dB	30	dBm
Output Third Order Intercept, OTOI @ 20dBm/Tone	42	dBm
Small Signal Gain Temperature Coefficient	-0.03	dB/°C
Noise Figure @ 19GHz	6	dB

TABLE III
THERMAL INFORMATION

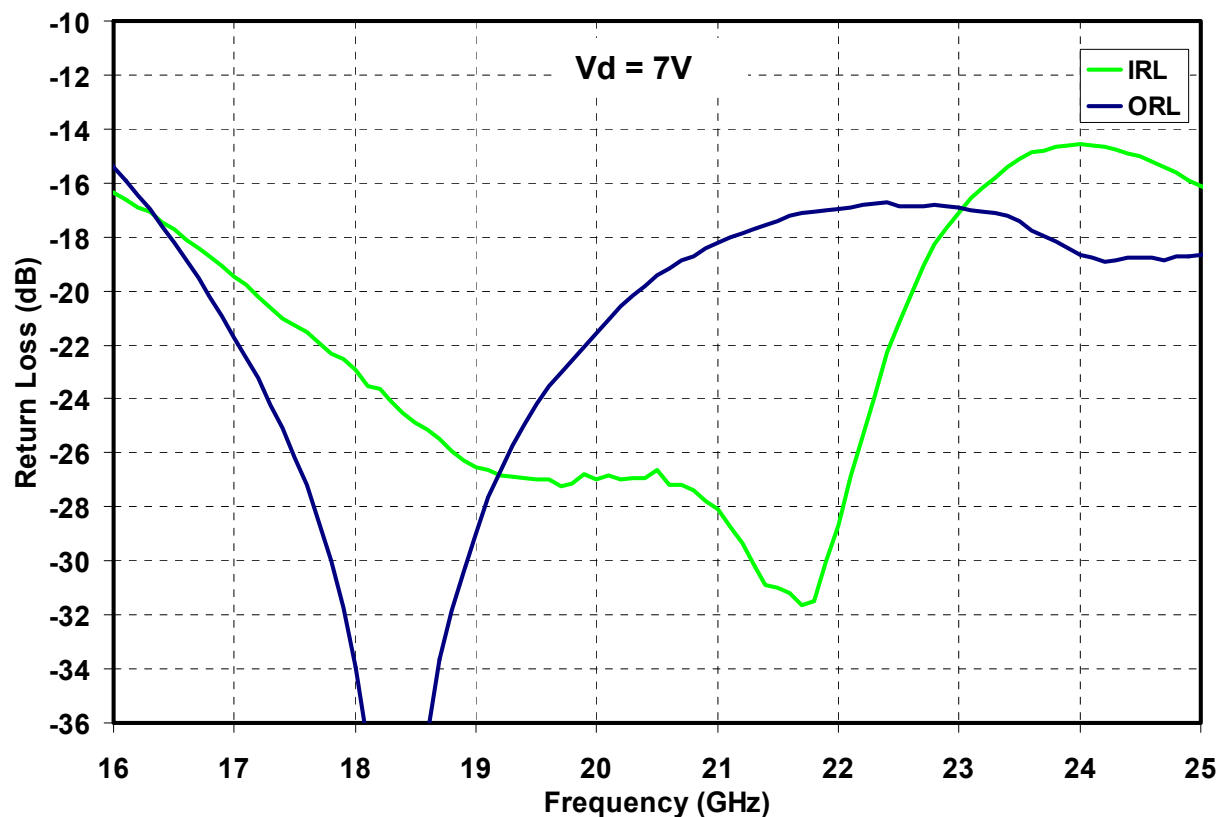
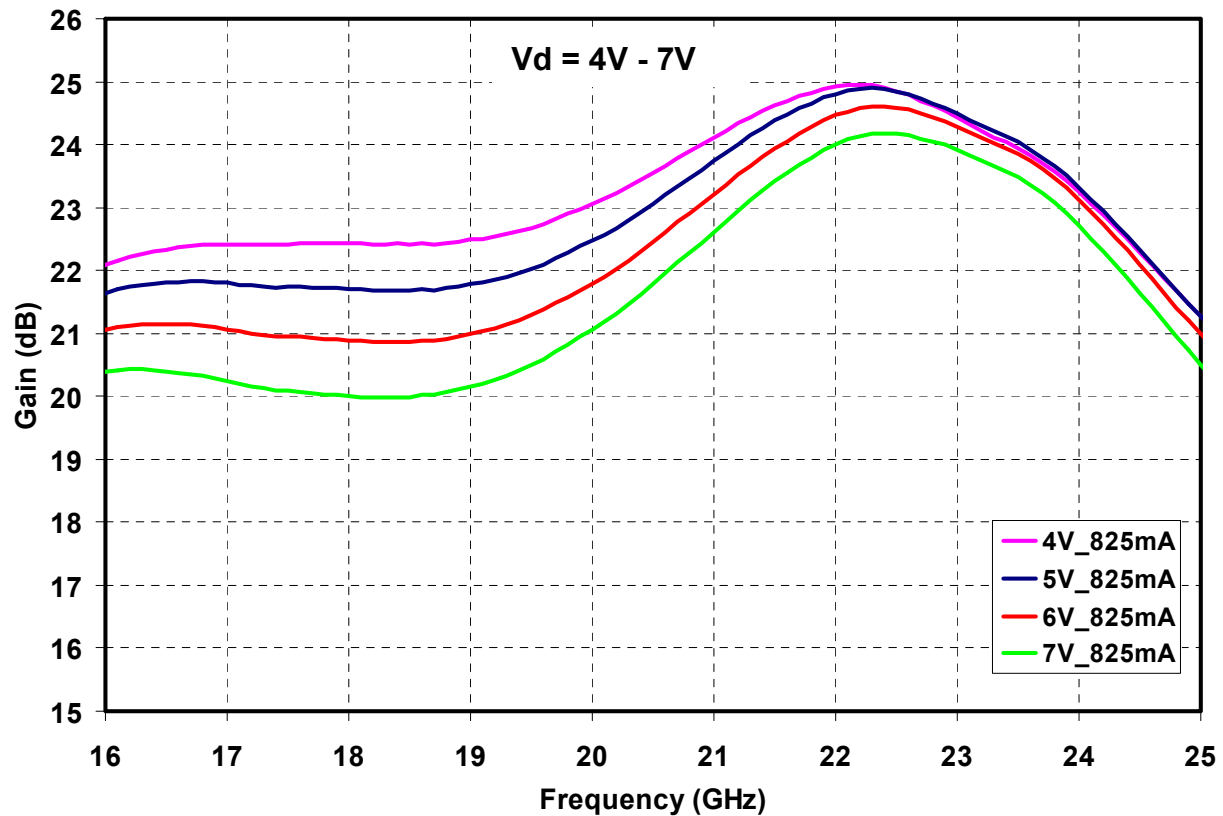
PARAMETER	TEST CONDITIONS	T _{CH} (°C)	θ _{JC} (°C/W)	T _M (HRS)
θ _{JC} Thermal Resistance (channel to Case)	Vd = 7 V Id = 825 mA P _{diss} = 5.78 W Small Signal	150	14.7	1.0E+6
θ _{JC} Thermal Resistance (channel to Case)	Vd = 7 V Id = 1050 mA @ Psat P _{out} = 1.6 W (RF) P _{diss} = 5.75 W	150	14.7	1.0E+6

Note: Assumes eutectic attach using 1.5 mil 80/20 AuSn mounted to a 20 mil CuMo Carrier at 65°C baseplate temperature.

Measured Data

TGA4530

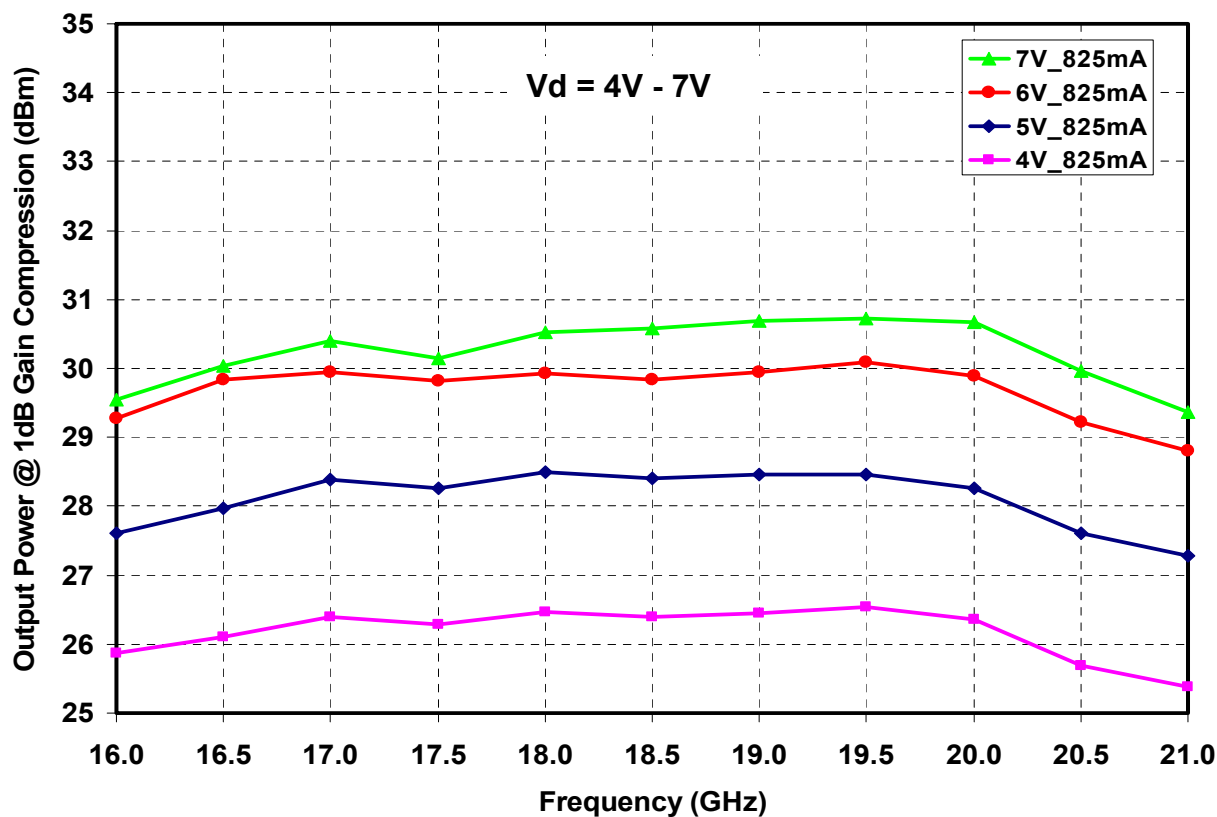
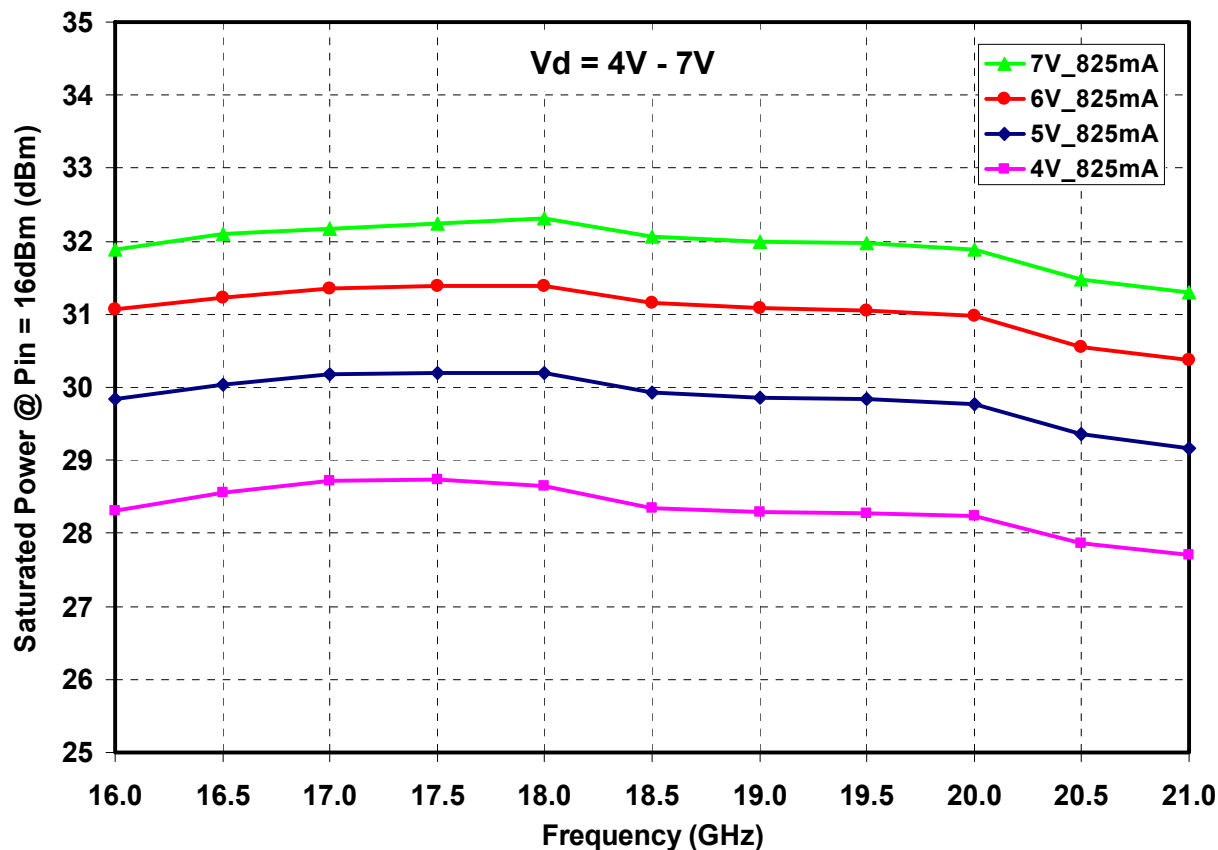
Bias Conditions: $I_{dq} = 825 \text{ mA}$



Measured Data

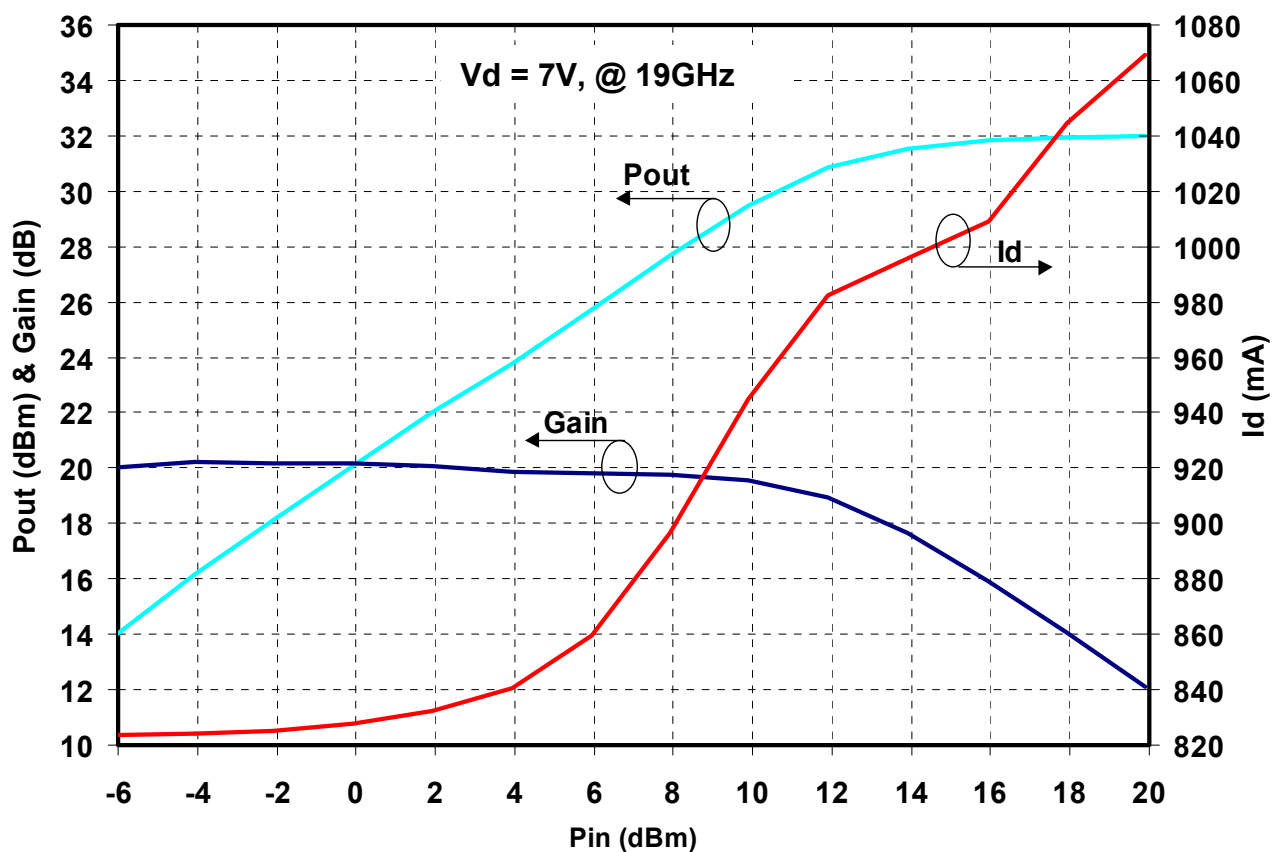
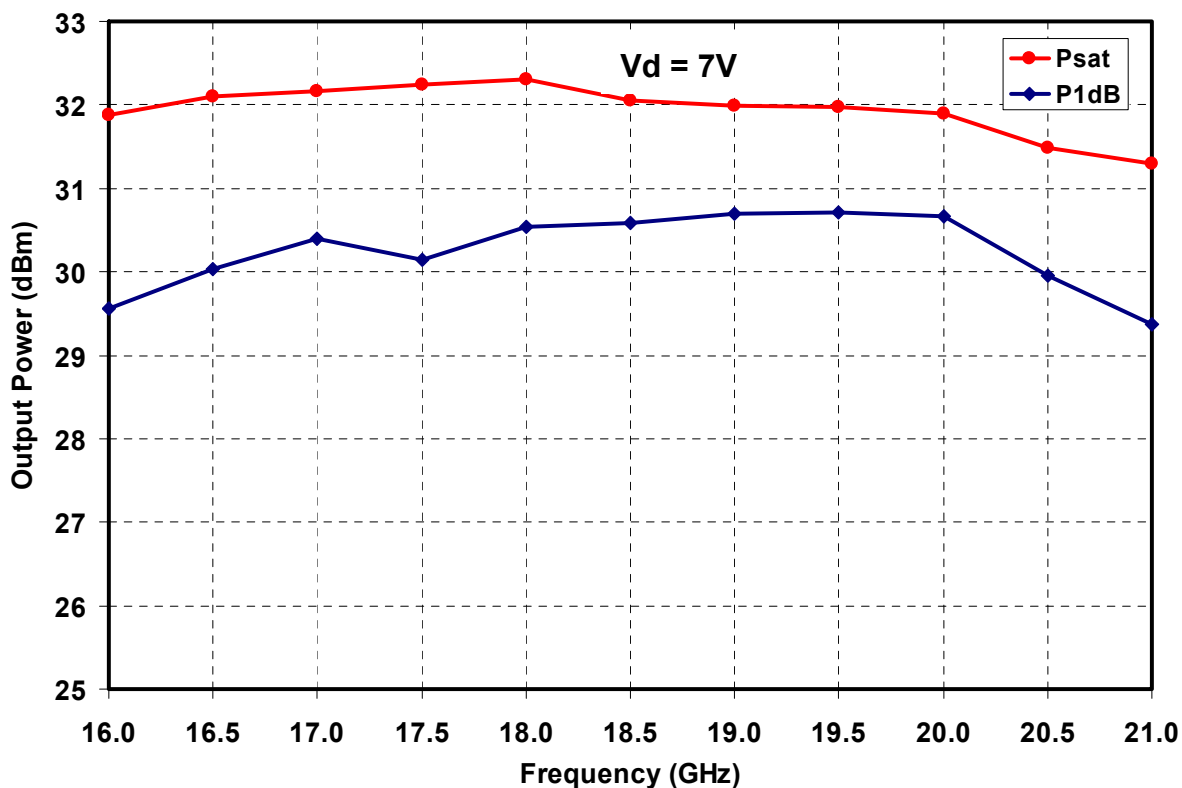
TGA4530

Bias Conditions: $V_d = 4V - 7V$, $I_{dq} = 825\text{ mA}$



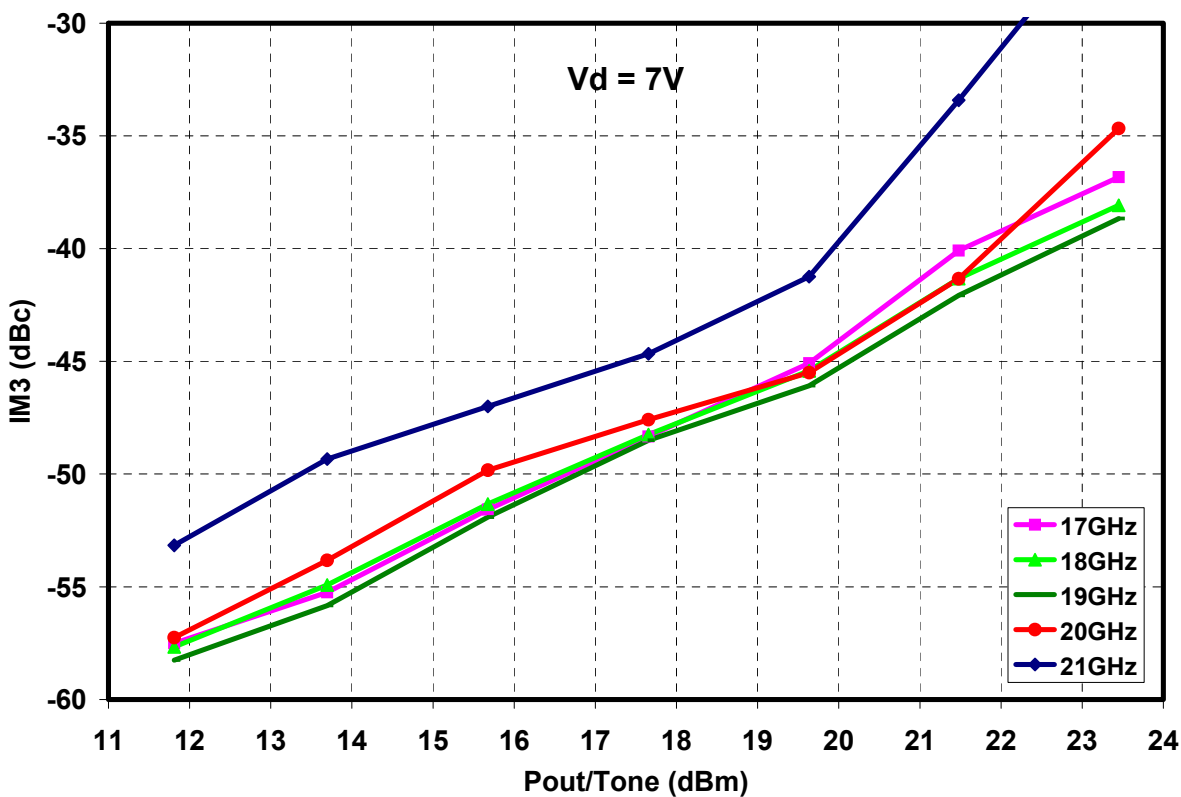
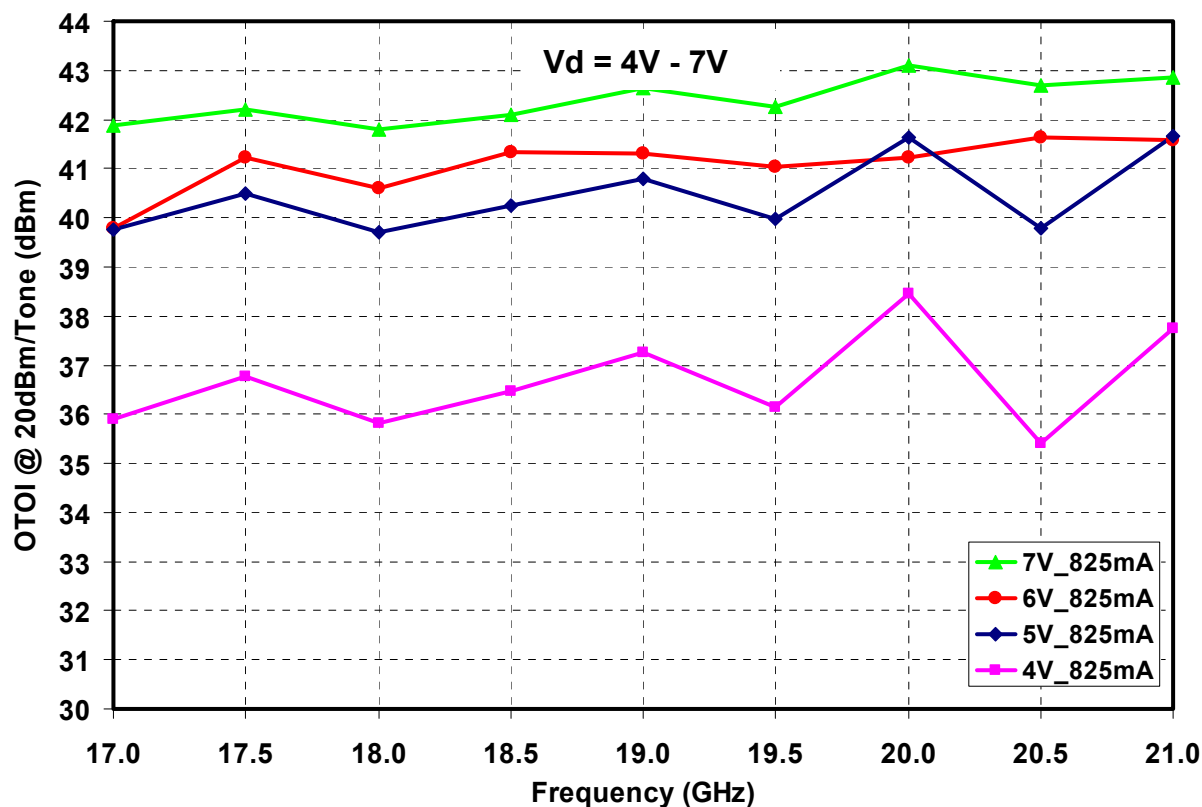
Measured Data

Bias Conditions: $V_d = 7V$, $I_{dQ} = 825\text{ mA}$



Measured Data

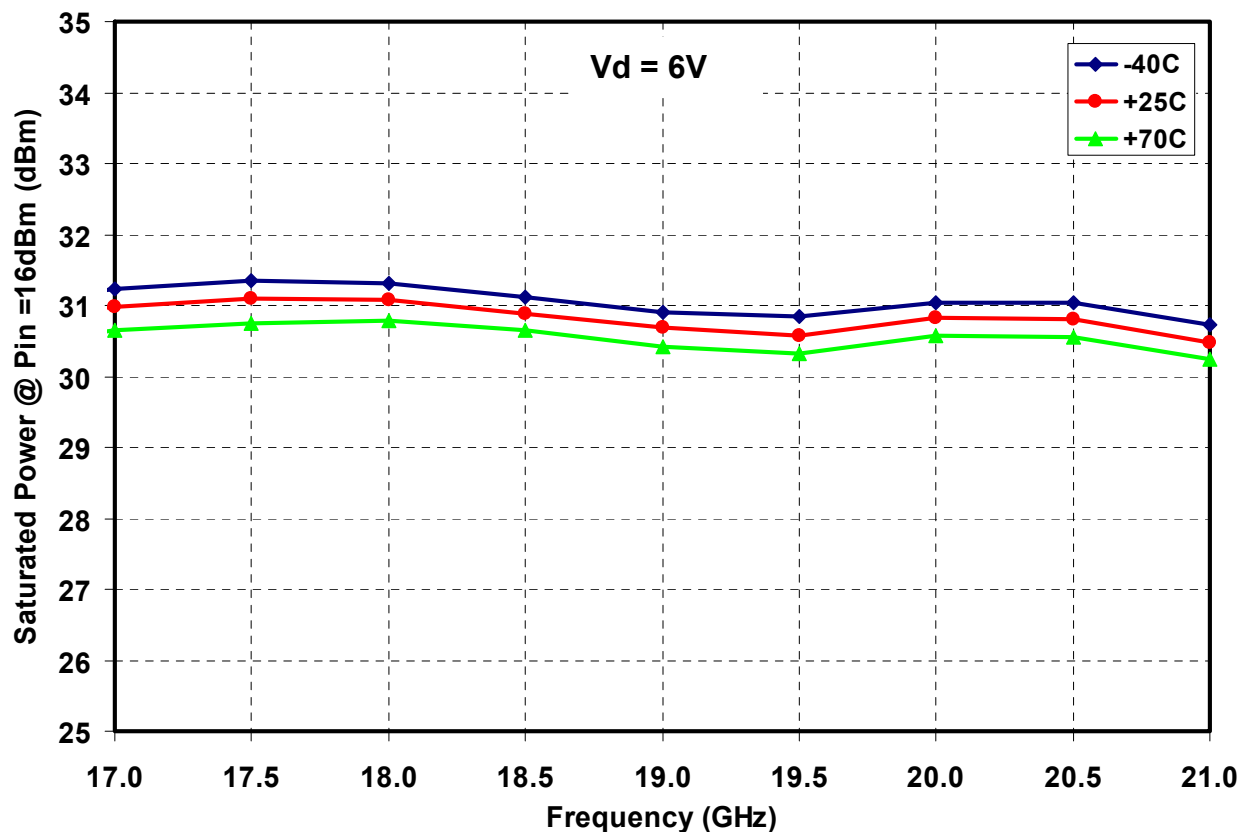
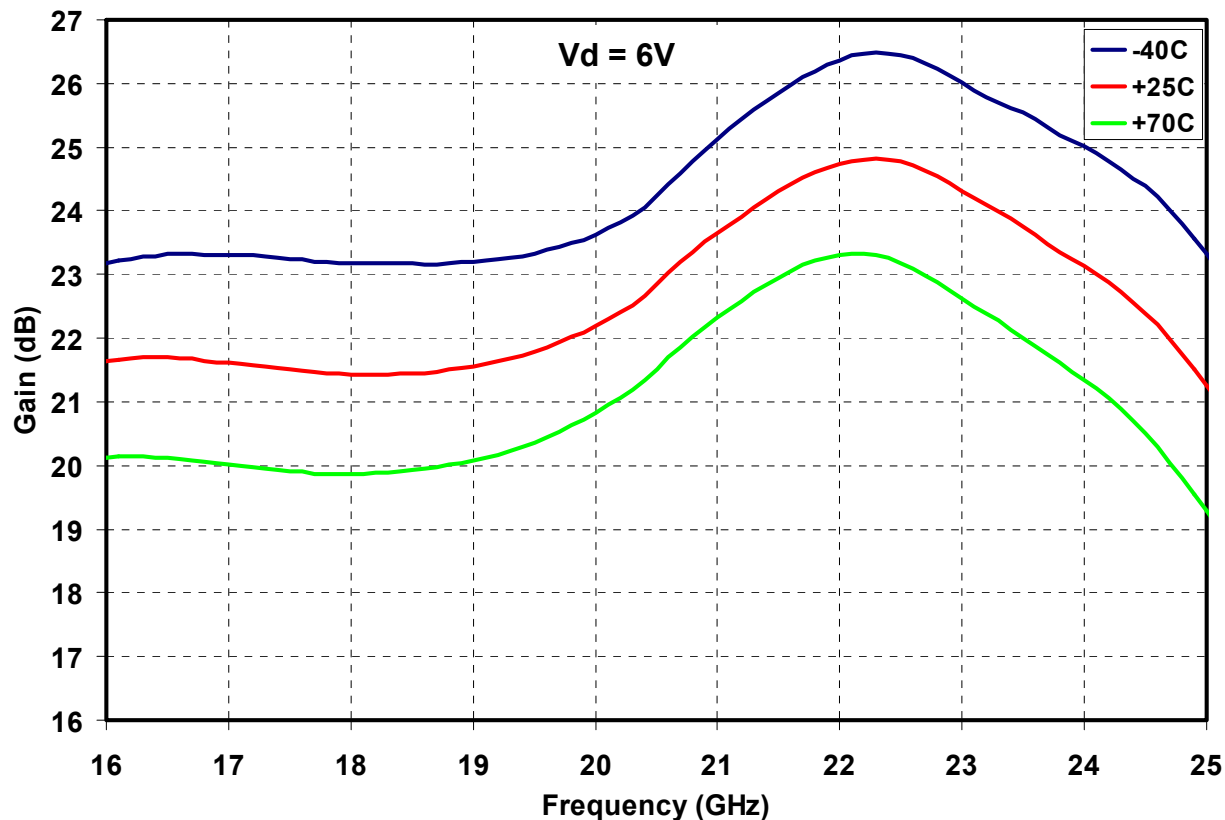
Bias Conditions: $V_d = 4V - 7V$, $I_{dq} = 825\text{ mA}$, $\Delta f = 1\text{ MHz}$



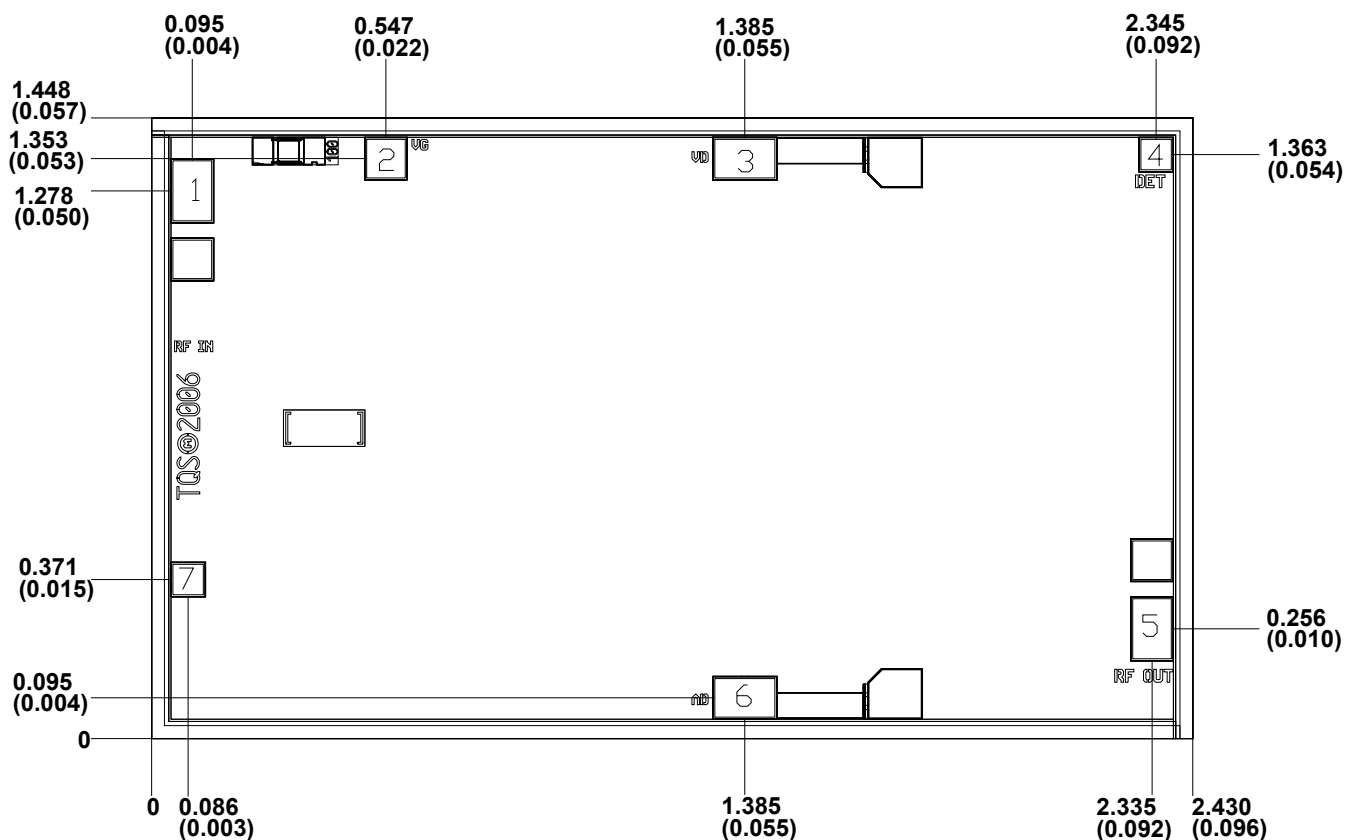
Measured Data

TGA4530

Bias Conditions: $V_d = 6V$, $I_{dq} = 825\text{ mA}$



Mechanical Drawing



Units: Millimeters (inches)

Thickness: 0.10 (0.004)

Chip edge to bond pad dimensions are shown to center of bond pad

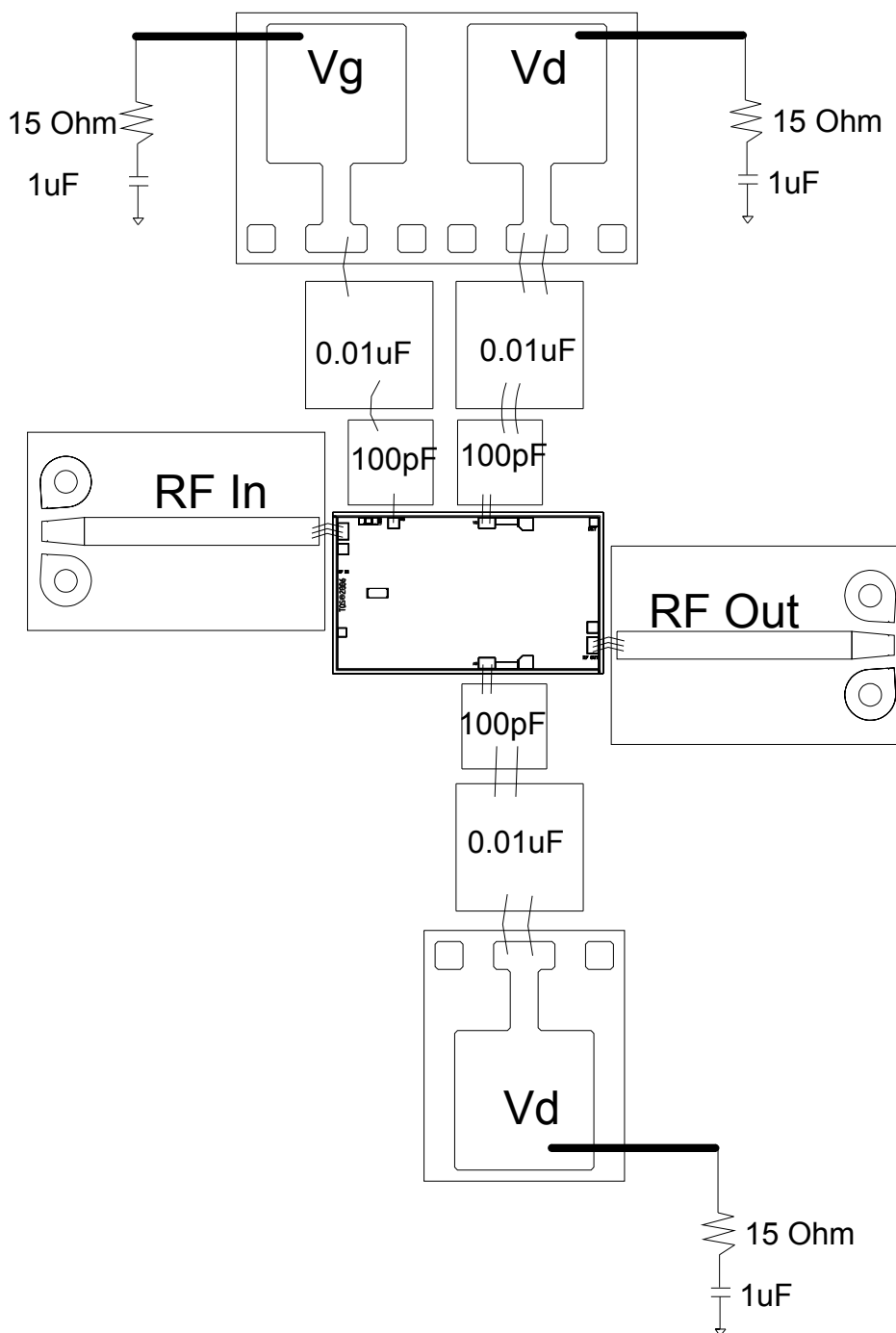
Chip size tolerance: +/- 0.05 (0.002)

GND IS BACKSIDE OF MMIC

Bond pad # 1	(RF Input)	0.100 x 0.150 (0.004 x 0.006)
Bond pad # 2	(Vg)	0.100 x 0.100 (0.004 x 0.004)
Bond pad # 3	(Vd)	0.150 x 0.100 (0.006 x 0.004)
Bond pad # 4	(Vdet)	0.081 x 0.081 (0.003 x 0.003)
Bond pad # 5	(RF Out)	0.100 x 0.150 (0.004 x 0.006)
Bond pad # 6	(Vd)	0.150 x 0.100 (0.006 x 0.004)
Bond pad # 7	(Vref)	0.081 x 0.081 (0.003 x 0.003)

GaAs MMIC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.

Recommended Assembly Diagram

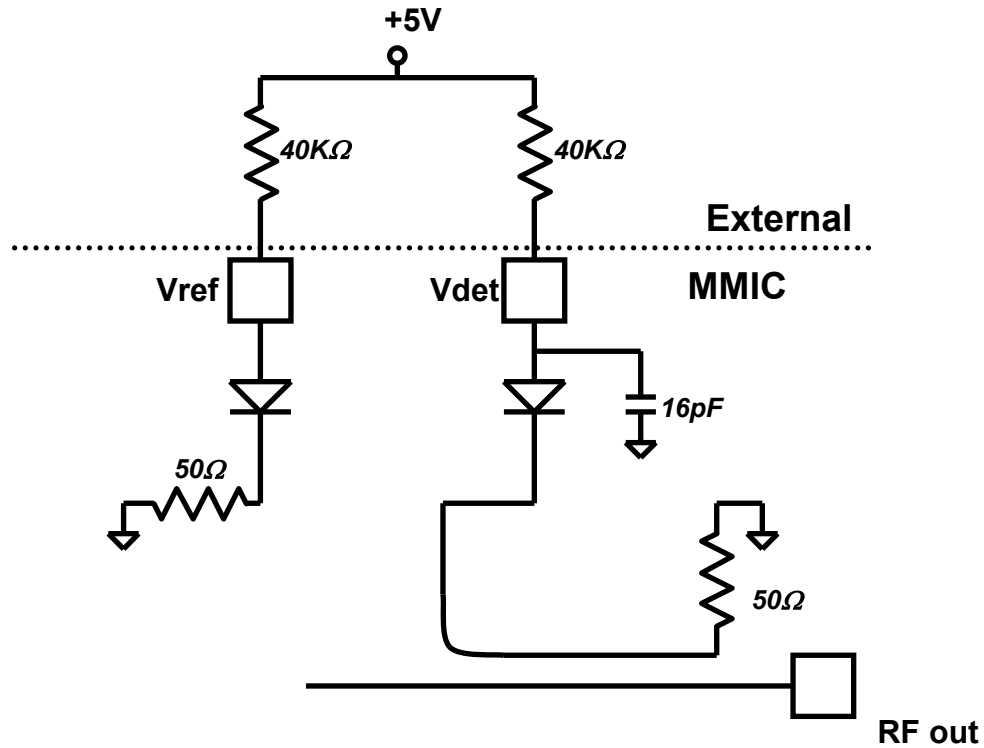


Vd = 5 to 7V

Id = 825mA

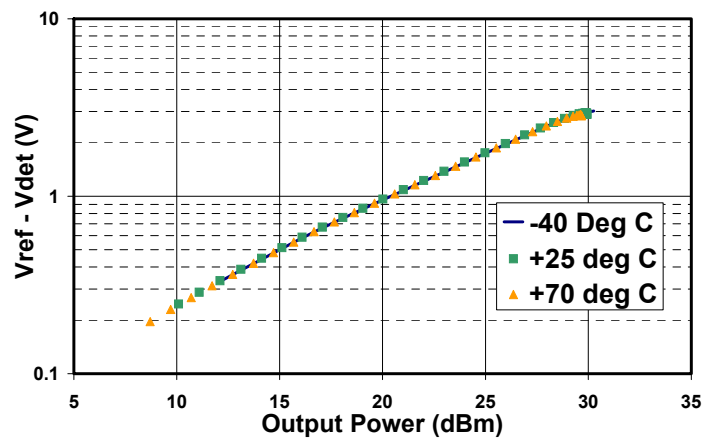
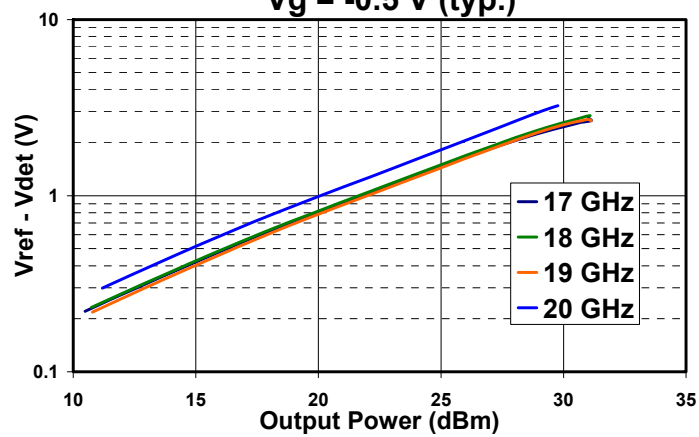
Vg = -0.45V (Typical for 7V Vd bias)

Power Detector



$V_d = 6V, I_d = 825mA$

$V_g = -0.5 V (typ.)$



Assembly Process Notes

Reflow process assembly notes:

- Use AuSn (80/20) solder with limited exposure to temperatures at or above 300⁰C (30 seconds max).
- An alloy station or conveyor furnace with reducing atmosphere should be used.
- No fluxes should be utilized.
- Coefficient of thermal expansion matching is critical for long-term reliability.
- Devices must be stored in a dry nitrogen atmosphere.

Component placement and adhesive attachment assembly notes:

- Vacuum pencils and/or vacuum collets are the preferred method of pick up.
- Air bridges must be avoided during placement.
- The force impact is critical during auto placement.
- Organic attachment can be used in low-power applications.
- Curing should be done in a convection oven; proper exhaust is a safety concern.
- Microwave or radiant curing should not be used because of differential heating.
- Coefficient of thermal expansion matching is critical.

Interconnect process assembly notes:

- Thermosonic ball bonding is the preferred interconnect technique.
- Force, time, and ultrasonics are critical parameters.
- Aluminum wire should not be used.
- Maximum stage temperature is 200⁰C.

Ordering Information

Part	Package Style
TGA4530	Chip